

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

**In re application of:** Cheng et al.

**Patent No.** 7,200,786

**Issued:** April 3, 2007

**Application No.** 10/749,283

**Filed:** December 30, 2003

**Confirmation No.** 9850

**For:** BUILT-IN SELF-ANALYZER FOR  
EMBEDDED MEMORY

**Examiner:** Phung M. Chung

**Art Unit:** 2138

**Attorney Reference No.** 1011-66273-01

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COMMISSIONER FOR PATENTS

REQUEST FOR CERTIFICATE OF CORRECTION

The following printing errors were noted in comparing the printed patent with the papers in the attorneys' files:

In the Claims:

Column 23, line 32, "The circuit of claim 39" should read --The circuit of claim 43--.

All of the above errors are attributable to the Patent Office, and a Certificate of Correction is enclosed to make formal notice of the errors in the referenced patent.

Respectfully submitted,

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UNITED STATES PATENT AND TRADEMARK OFFICE  
**CERTIFICATE OF CORRECTION**

PATENT NO. : 7,200,786  
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INVENTOR(S) : Cheng et al.

Page 1 of 1

It is certified that an error appears or errors appear in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

In the Claims:

Column 23, line 32, "The circuit of claim 39" should read --The circuit of claim 43--.

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